

In re United States Patent Application of:)	Docket No.:	2771-688
Applicants:	KING, Mackenzie, et al.)	Conf. No.:	7009
Application No.:	10/722,174)	Art Unit:	1742
Date Filed:	November 25, 2003)	Examiner:	Nicholas A. Smith
Title:	ON-WAFER)	Customer No.:	
	ELECTROCHEMICAL)		
	DEPOSITION PLATING)		
	METROLOGY PROCESS)		
	AND APPARATUS)		
)		

I hereby certify that this document is being filed via EFS in the United States Patent and Trademark Office on March 10, 2008.
/Steven J. Hultquist/

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Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

This responds to the November 9, 2007 Office Action in the above-identified application. A petition for one month extension of time is hereby requested under the provisions of 37 CFR 1.136, extending the period for reply to the Office Action from February 9, 2008 to March 10, 2008. The fee specified in 37 CFR 1.17(a)(2) for such extension of time is being paid by on-line payment at the time of EFS filing of this response.

A listing of the claims of the above-identified patent application are set out in **Section I (Listing of the Claims)** hereof.

Remarks concerning the substance of the November 9, 2007 Office Action and patentable distinction of the pending claims are set out in **Section II (Remarks)** hereof.